Sear	ch v	lotes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/560,619	OZAWA ET AL.
Examiner	Art Unit
Karuna P. Reddy	1713

SEARCHED					
Class	Subclass	Date	Examiner		
,					
		-			
	<u>.</u>				

INTERFERENCE SEARCHED				
Subclass	Date	Examiner		
•	,			
· · · · · · · · · · · · · · · · · · ·				
ļ				
	Subclass	Subclass Date		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST, Inventor's search, PALM	2/12/2007	KR
524/(522, 523)	2/12/2007	KR
·		